High Performance 512x8 PROM TiW PROM Family

53/63S480
53/63S481
53/63S481A

Features/Benefits

- 30 ns maximum access time
- Reliable titanium-tungsten fuses (TiW) guarantees greater than 98% programming yields
- Low voltage generic programming
- Pin-compatible with standard Schottky PROMs
- PNP inputs for low input current
- Open collector or three-state outputs
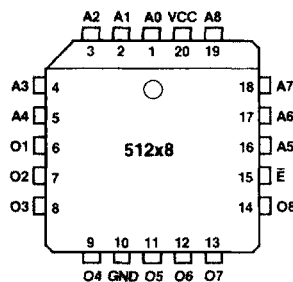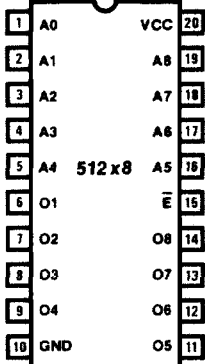
Applications

- Microprogram control store
- Microprocessor program store
- Look-up table
- Character generator
- Code converter
- Programmable Logic Element (PLE™) with 9 inputs, 8 outputs, and 512 product terms per output
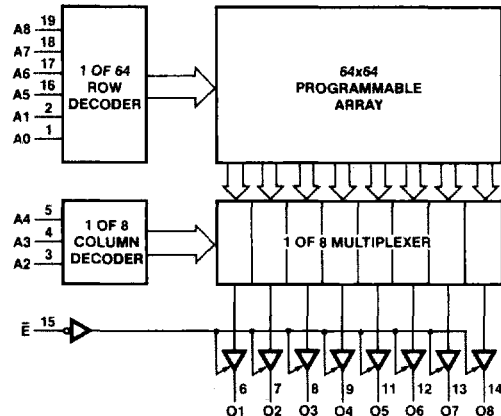
Description

The 53/63S480 and 53/63S481/A are 512x8 bipolar PROMs featuring low input current PNP inputs, full Schottky clamping, and open collector or three-state outputs. The titanium-tungsten fuses store a logical low and are programmed to the high state. Special on-chip circuitry and extra fuses provide preprogramming testing which assures high programming yields and high reliability.

The 63 series is specified for operation over the commercial temperature and voltage range. The 53 series is specified for the military ranges.

Programming

The 53/63S480 and 53/63S481/A PROMs are programmed with the same programming algorithm as all other Monolithic Memories' generic TiW PROMs. For details contact the factory.

Selection Guide

MEMORY		PACKAGE		OUTPUT	PERFORMANCE	PART NUMBER	
SIZE	ORGANIZATION	PINS	TYPE			0°C to +75°C	-55°C to +125°C
4K	512x8	20	N,J NL,L*, F*	TS	Enhanced	63S481A	53S481A
					Standard	63S481	53S481
				OC		63S480	53S480

*Contact factory for package dimensions.

Pin Configurations

Block Diagram

Absolute Maximum Ratings

	Operating	Programming
Supply voltage V_{CC}	-0.5 V to 7 V	12 V
Input voltage	-1.5 V to 7 V	7 V
Input current	-30 mA to $+5$ mA	
Off-state output voltage	-0.5 V to 5.5 V	12 V
Storage temperature	$-65°$ to $+150°$C	

Operating Conditions

SYMBOL	PARAMETER	MILITARY MIN	NOM	MAX	COMMERCIAL MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
T_A	Operating free-air temperature	-55		125	0		75	°C

DC Electrical Characteristics Over Operating Conditions

SYMBOL	PARAMETER	TEST CONDITION			MIN	TYP†	MAX	UNIT
V_{IL}	Low-level input voltage	Guaranteed input logical low voltage for all inputs††					0.8	V
V_{IH}	High-level input voltage	Guaranteed input logical high voltage for all inputs††			2			V
V_{IC}	Input clamp voltage	V_{CC} = MIN	I_I = -18 mA				-1.5	V
I_{IL}	Low-level input current	V_{CC} = MAX	V_I = 0.4 V				-0.25	mA
I_{IH}	High-level input current	V_{CC} = MAX	V_I = V_{CC} MAX				40	μA
V_{OL}	Low-level output voltage	V_{CC} = MIN	I_{OL} = 16 mA	Com			0.45	V
				Mil			0.5	
V_{OH}	High-level output voltage*	V_{CC} = MIN	Com I_{OH} = -3.2 mA		2.4			V
			Mil I_{OH} = -2 mA					
I_{OZL}	Off-state output current*	V_{CC} = MAX	V_O = 0.4 V				-40	μA
I_{OZH}			V_O = 2.4 V				40	
I_{CEX}	Open collector output current	V_{CC} = MAX	V_O = 2.4 V				40	μA
			V_O = 5.5 V				100	
I_{OS}	Output short-circuit current**	V_{CC} = 5 V	V_O = 0 V		-20		-90	mA
I_{CC}	Supply current	V_{CC} = MAX. All inputs grounded. All outputs open.				104	155	mA

Switching Characteristics Over Operating Conditions (See standard test load)

OPERATING CONDITIONS	DEVICE TYPE	t_{AA} (ns) ADDRESS ACCESS TIME		t_{EA} AND t_{ER} (ns) ENABLE ACCESS TIME RECOVERY TIME		UNIT
		TYP†	MAX	TYP†	MAX	
COMMERCIAL	63S481A	22	30	18	25	ns
	63S480, 63S481	22	45	18	25	
MILITARY	53S481A	22	40	18	30	
	53S480, 53S481	22	50	18	35	

* Three-state only   ** Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.
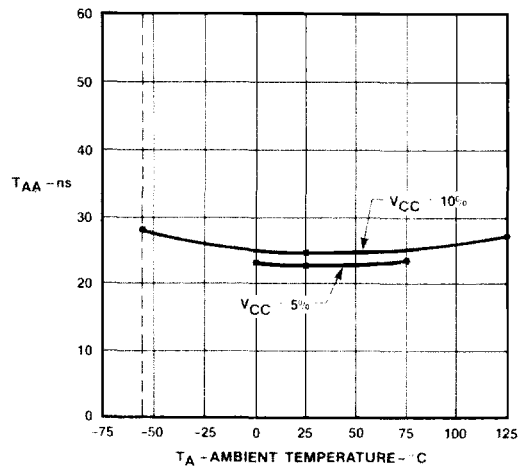
† Typicals at 5.0 V V_{CC} and 25°C T_A.

†† V_{IL} and V_{IH} limits are absolute values with respect to the device ground pin(s) and includes all overshoots due to test equipment noise.
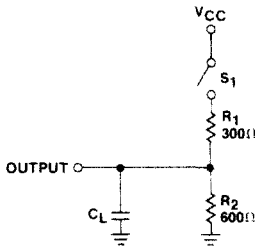
Typical I_{CC} vs Temperature
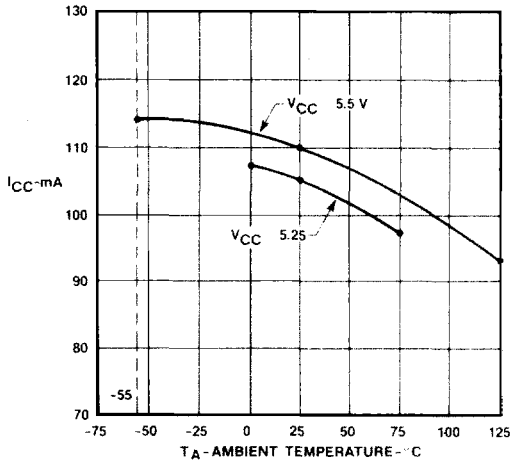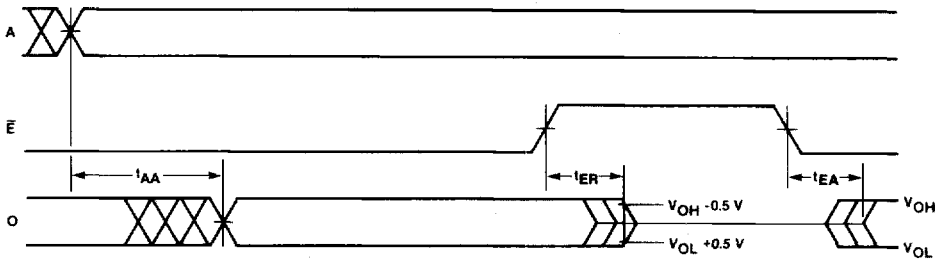

Typical T_{AA} vs Temperature

Switching Test Load

Definition of Timing Diagram

WAVEFORM	INPUTS	OUTPUTS
	DON'T CARE; CHANGE PERMITTED	CHANGING; STATE UNKNOWN
	NOT APPLICABLE	CENTER LINE IS HIGH IMPEDANCE STATE
	MUST BE STEADY	WILL BE STEADY

Definition of Waveforms

NOTES. 1. Input pulse amplitude 0 V to 3.0 V.

2. Input rise and fall times 2-5 ns from 0.8 V to 2.0 V.

3. Input access measured at the 1.5 V level.

4. t_{AA} is tested with switch S_1 closed, C_L = 30 pF and measured at 1.5 V output level.

5. For open collector devices, TEA and TER are measured at the 1 5 V output level with S_1 closed and C_L = 30 pF.

6. For three-state devices. TEA is measured at the 1.5 V output level with C_L = 30 pF S_1 is open for high-impedance to "1" test
   and closed for high-impedance to "0" test.

   TER is tested with C_L = 5 pF. S_1 is open for "1" to high-impedance test, measured at V_{OH} -0.5 V output level; S_1 is closed for "0" to
   high-impedance test measured at V_{OL} +0.5 V output level

Commercial Programmers

Monolithic Memories PROMs are designed and tested to give a programming yield greater than 98%. If your programming yield is lower, check your programmer. It may not be properly calibrated.

Programming is final manufacturing — it must be quality-controlled. Equipment must be calibrated as a regular

PROM PROGRAMMING EQUIPMENT INFORMATION

SOURCE AND LOCATION

Data I/O Corp.
10525 Willows Rd. N.E.
Redmond, WA 98073

Kontron Electronics, Inc.
630 Price Ave.
Redwood City, CA 94063

routine, ideally under the actual conditions of use. Each time a new board or a new programming module is inserted, the whole system should be checked. Both timing and voltages must meet published specifications for the device.

Remember — The best PROMs available can be made unreliable by improper programming techniques.

Digelec Inc.
586 Weddell Dr.
Suite 1
Sunnyvale, CA 94089

Metal Mask Layout